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Application/Control No.	Applicant(s)/Patent under Reexamination
10/722,155	SANA ET AL.
Examiner	Art Unit
Young I Kim	1637

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SEARCH NOT (INCLUDING SEARCH		)
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Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) see enclosed for text-search strategy	3/2/2007	YJK
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